



# Moving from Windows® XP to Windows 7? Don't Forget about Your 4200-SCS Parameter Analyzer

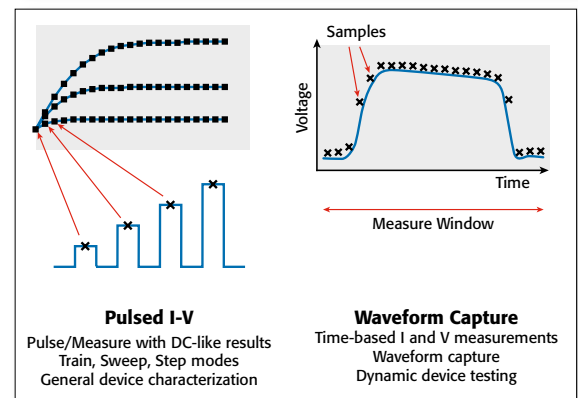
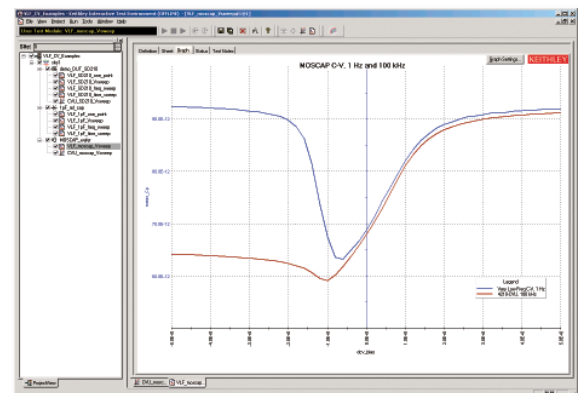
Microsoft support of Windows XP ends in April 2014. If you're planning to migrate your PC to Windows 7, there's a way to breathe new life into your favorite parameter analyzer, as well. Regardless of how long ago it was purchased, your Model 4200-SCS can be upgraded with the latest software and hardware, providing you an easy migration path to meet today's characterization challenges.

## Your upgraded Model 4200-SCS running on Windows 7 expands your measurement capabilities to include:

- Capacitance vs. voltage (C-V) measurements\*
- Ramp rate quasistatic C-V measurements
- Very-low frequency C-V measurements
- Ultra-fast pulsed I-V measurements\*
- Easy switching between I-V, C-V, and pulsed I-V measurements\*
- Built-in diagnostic tools for C-V and pulsed I-V
- Waveform capture and segment arbitrary waveform generation
- Over 450 application tests, including non-volatile memory, pulsed I-V, BJT, MOSFET, nanotech, reliability, resistivity, pulse, solar, discrete components, and more
- Higher capacity internal memory and hard drive
- Parameter extraction samples

\* Instrument modules sold separately

**Aligned with Innovation** Keithley's ongoing commitment to our customers and the Model 4200-SCS Parameter Analyzer assures you of cost-effective system upgrade paths that align with new and future test challenges.



Learn what upgrade options are available for your Model 4200-SCS. Contact your local Keithley or Tektronix representative with your system's serial number today or visit [www.keithley.com/buy](http://www.keithley.com/buy).

**If you have KTEI 4.x or 5.0, your system is limited to DC I-V measurements only. Here's a way to expand your capabilities:**

<b>KTEI 9.0 upgrade provides these new features:</b>	<b>Capabilities and instrument cards that are supported with KTEI 9.0*</b>
<ul style="list-style-type: none"> <li>• Nine instrument slots for expanded measurement capability</li> <li>• Access to over 450 application tests: BJT, MOSFET, Non-volatile Memory, Nanotech, Reliability, Resistivity, Pulse, Solar, Discrete Components</li> <li>• Parameter extraction examples</li> <li>• Pulse timing preview mode</li> <li>• Segment Arbitrary Waveform preview mode</li> <li>• Pulse dual sweep for hysteresis investigation</li> <li>• New high resolution display</li> <li>• High capacity power supply to support multiple pulse and high power SMU modules</li> <li>• Four USB ports</li> <li>• Higher capacity internal memory and hard drive</li> <li>• Windows 7 operating system</li> </ul>	<ul style="list-style-type: none"> <li>• Capacitance vs. Voltage measurements with 4210-CVU module</li> <li>• Ramp Rate Quasistatic C-V measurements</li> <li>• Very-Low Frequency C-V measurements</li> <li>• Ultra-fast Pulsed I-V measurements with 4225-PMU – up to 12 synchronized channels</li> <li>• Switch between I-V, C-V, and Pulsed I-V with 4225-RPM</li> <li>• Built-in diagnostic tools for C-V and Pulsed I-V measurements</li> <li>• Waveform capture with 4225-PMU</li> <li>• Segment Arbitrary Waveform with source and measure capability with 4225-PMU</li> <li>• Dual channel Pulse Generator module 4220-PGU</li> <li>• Two channel Oscilloscope module 4200-SCP2 and 4200-SCP2HR</li> <li>• Ultra-fast Bias Temperature Instability measurement 4200-BTI-A</li> <li>• Multi-measurement Performance Cables for connecting to the device under test – MMPC kits</li> </ul>

**If you have KTEI 6.0, 6.1, 6.2, here's a way to include C-V and Ultra-Fast Pulsed I-V capabilities:**

<b>KTEI 9.0 upgrade provides these new features:</b>	<b>Capabilities and instrument cards that are supported with KTEI 9.0*</b>
<ul style="list-style-type: none"> <li>• Nine instrument slots for expanded measurement capability</li> <li>• Access to over 450 application tests: BJT, MOSFET, Non-volatile Memory, Nanotech, Reliability, Resistivity, Pulse, Solar, Discrete Components</li> <li>• Parameter extraction examples</li> <li>• Pulse timing preview mode</li> <li>• Segment Arbitrary Waveform preview mode</li> <li>• Pulse dual sweep for hysteresis investigation</li> <li>• New high resolution display</li> <li>• High capacity power supply to support multiple pulse and high power SMU modules</li> <li>• Four USB ports</li> <li>• Higher capacity internal memory and hard drive</li> <li>• Windows 7 operating system</li> </ul>	<ul style="list-style-type: none"> <li>• Capacitance vs. Voltage measurements with 4210-CVU module</li> <li>• Ramp Rate Quasistatic C-V measurements</li> <li>• Very-Low Frequency C-V measurements</li> <li>• Ultra-fast Pulsed I-V measurements with 4225-PMU – up to 12 synchronized channels</li> <li>• Switch between I-V, C-V, and Pulsed I-V with 4225-RPM</li> <li>• Built-in diagnostic tools for C-V and Pulsed I-V measurements</li> <li>• Waveform capture with 4225-PMU</li> <li>• Segment Arbitrary Waveform with source and measure capability with 4225-PMU</li> <li>• Ultra-fast Bias Temperature Instability measurement 4200-BTI-A</li> <li>• Multi-measurement Performance Cables for connecting to the device under test</li> </ul>

**If you have KTEI 7.0, 7.1, 7.2, here's a way to expand to Ultra-fast pulsed I-V capabilities:**

<b>KTEI 9.0 upgrade provides these new features:</b>	<b>Capabilities and instrument cards that are supported with KTEI 9.0*</b>
<ul style="list-style-type: none"> <li>• Access to over 450 application tests: BJT, MOSFET, Non-volatile Memory, Nanotech, Reliability, Resistivity, Pulse, Solar, Discrete Components</li> <li>• Parameter extraction examples</li> <li>• Pulse timing preview mode</li> <li>• Segment Arbitrary Waveform preview mode</li> <li>• Pulse dual sweep for hysteresis investigation</li> <li>• High capacity power supply to support multiple pulse and high power SMU modules</li> <li>• Higher capacity internal memory and hard drive</li> <li>• Windows 7 operating system</li> </ul>	<ul style="list-style-type: none"> <li>• Very-Low Frequency C-V measurements</li> <li>• Ultra-fast Pulsed I-V measurements with 4225-PMU – up to 12 synchronized channels</li> <li>• Switch between I-V, C-V, and Pulsed I-V with 4225-RPM</li> <li>• Built-in diagnostic tools for Pulsed I-V measurements</li> <li>• Waveform capture with 4225-PMU</li> <li>• Segment Arbitrary Waveform with source and measure capability with 4225-PMU</li> <li>• Ultra-fast Bias Temperature Instability measurement 4200-BTI-A</li> <li>• Multi-measurement Performance Cables for connecting to the device under test</li> </ul>

**If you have KTEI 8.0, 8.1, 8.2, here's a way to include additional Pulse capabilities and migrate to Windows 7:**

<b>KTEI 9.0 provides these new features:</b>	<b>Capabilities and instrument cards that are supported with KTEI 9.0*</b>
<ul style="list-style-type: none"> <li>• New application tests: Non-volatile Memory, Pulsed I-V</li> <li>• Pulse timing preview mode</li> <li>• Segment Arbitrary Waveform preview mode</li> <li>• Pulse dual sweep for hysteresis investigation</li> <li>• Higher capacity internal memory and hard drive</li> <li>• Windows 7 operating system</li> </ul>	<ul style="list-style-type: none"> <li>• Very-Low Frequency C-V measurements</li> <li>• Ultra-fast Pulsed I-V measurements with 4225-PMU – up to 12 synchronized channels</li> <li>• Switch between I-V, C-V, and Pulsed I-V with 4225-RPM</li> <li>• Built-in diagnostic tools for Pulsed I-V measurements</li> <li>• Waveform capture with 4225-PMU</li> <li>• Segment Arbitrary Waveform with source and measure capability with 4225-PMU</li> <li>• Ultra-fast Bias Temperature Instability measurement 4200-BTI-A</li> <li>• Multi-measurement Performance Cables for connecting to the device under test</li> </ul>

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